

William Stallings  
Computer Organization  
and Architecture

9th Edition



# + Chapter 5

## Internal Memory

# + Memory Cell Operation

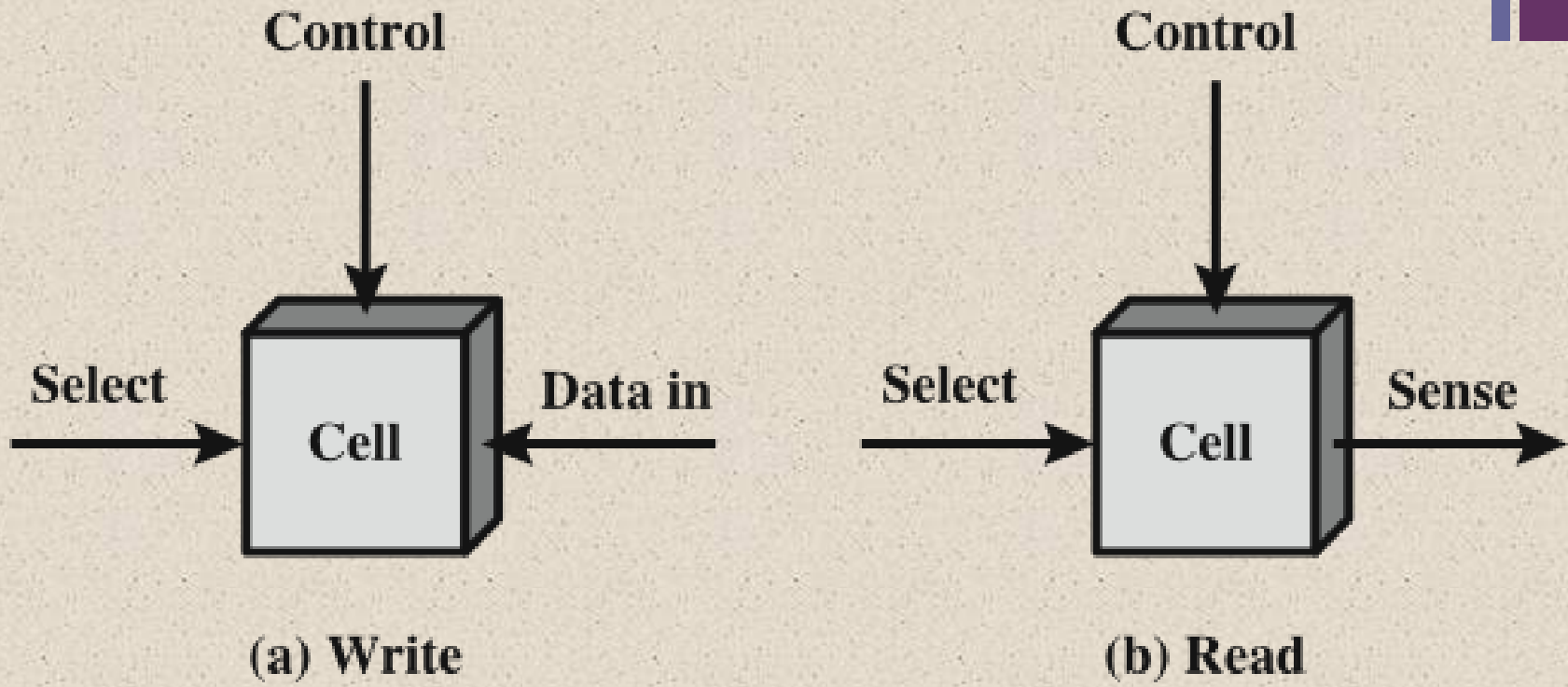


Figure 5.1 Memory Cell Operation

# Semiconductor Memory Types

Memory Type	Category	Erasure	Write Mechanism	Volatility
Random-access memory (RAM)	Read-write memory	Electrically, byte-level	Electrically	Volatile
Read-only memory (ROM)	Read-only memory	Not possible	Masks	Nonvolatile
Programmable ROM (PROM)			Electrically	
Erasable PROM (EPROM)	UV light, chip-level			
Electrically Erasable PROM (EEPROM)	Electrically, byte-level			
Flash memory	Electrically, block-level			

Table 5.1 Semiconductor Memory Types



# Dynamic RAM (DRAM)



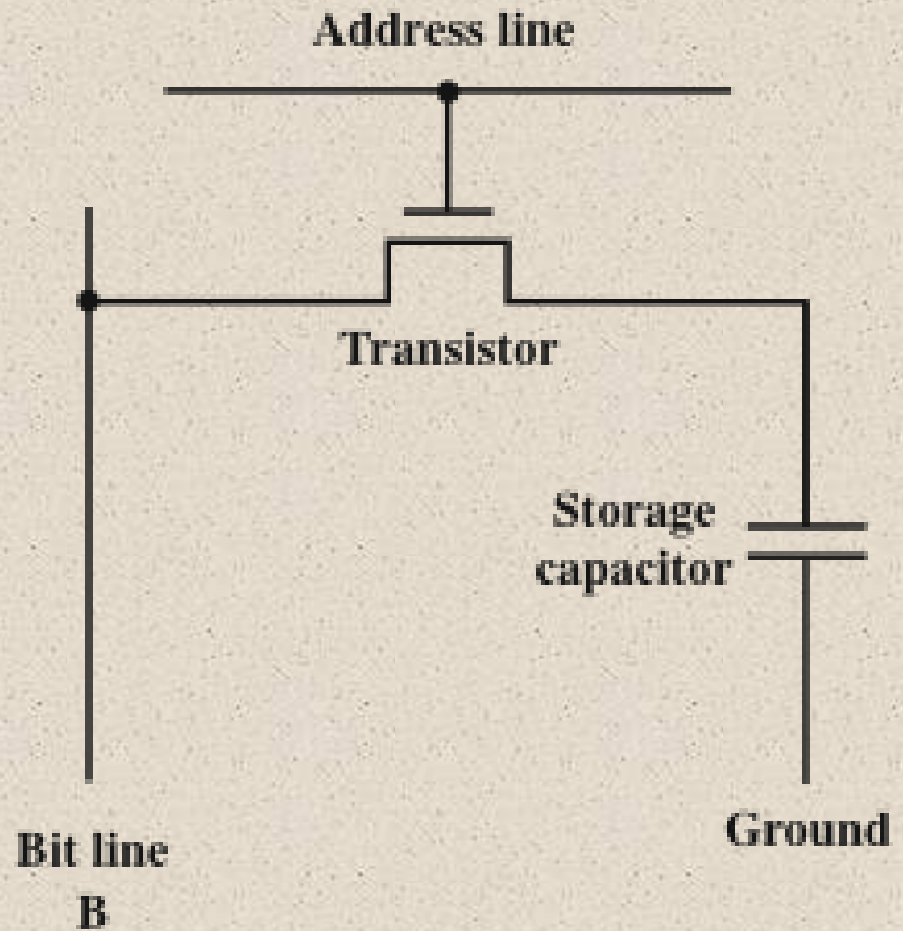
- RAM technology is divided into two technologies:
  - Dynamic RAM (DRAM)
  - Static RAM (SRAM)
- DRAM
  - Made with cells that store data as charge on capacitors
  - Presence or absence of charge in a capacitor is interpreted as a binary 1 or 0
  - Requires periodic charge refreshing to maintain data storage
  - The term *dynamic* refers to tendency of the stored charge to leak away, even with power continuously applied



# Dynamic RAM Structure

Figure 5.2a

Typical Memory Cell Structures

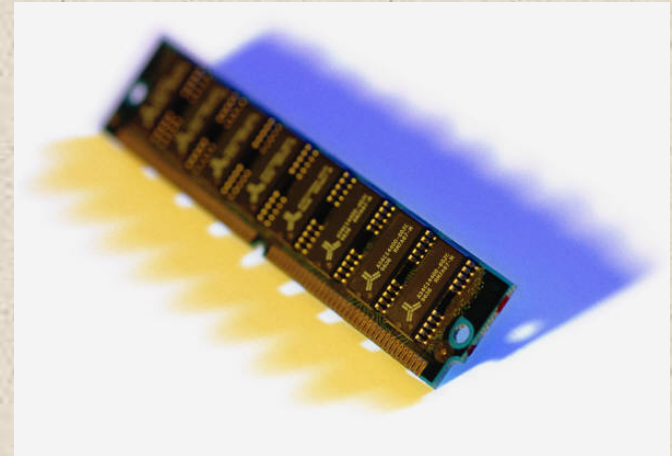


(a) Dynamic RAM (DRAM) cell



# Static RAM (SRAM)

- Digital device that uses the same logic elements used in the processor
- Binary values are stored using traditional flip-flop logic gate configurations
- Will hold its data as long as power is supplied to it

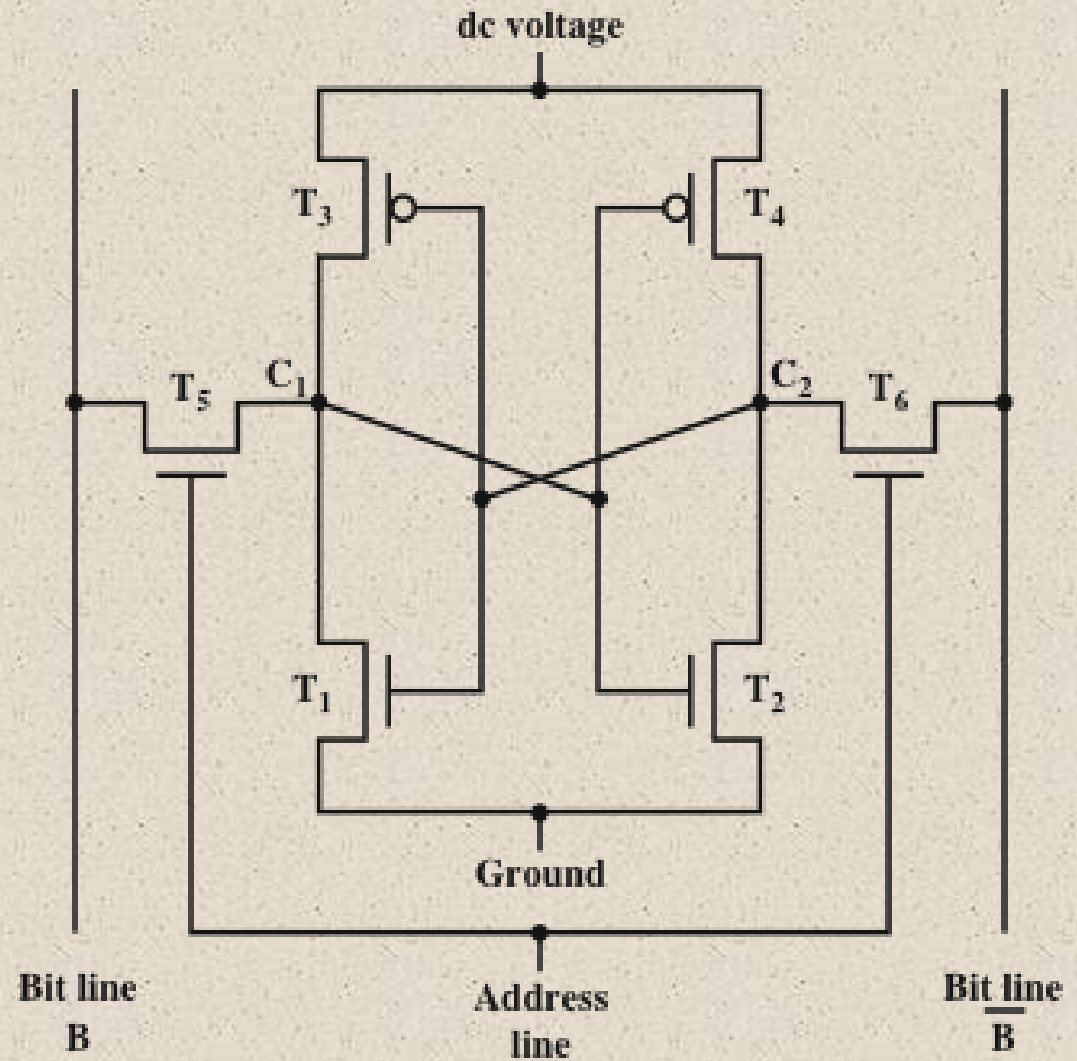




# Static RAM Structure

Figure 5.2b

Typical Memory Cell Structures



(b) Static RAM (SRAM) cell



# SRAM versus DRAM

- Both volatile
  - Power must be continuously supplied to the memory to preserve the bit values
- Dynamic cell
  - Simpler to build, smaller
  - More dense (smaller cells = more cells per unit area)
  - Less expensive
  - Requires the supporting refresh circuitry
  - Tend to be favored for large memory requirements
  - Used for main memory
- Static
  - Faster
  - Used for cache memory (both on and off chip)

SRAM

DRAM



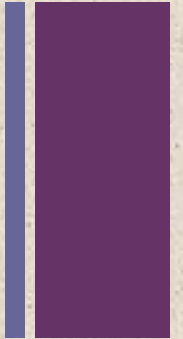
# Read Only Memory (ROM)



- Contains a permanent pattern of data that cannot be changed or added to
- No power source is required to maintain the bit values in memory
- Data or program is permanently in main memory and never needs to be loaded from a secondary storage device
- Data is actually wired into the chip as part of the fabrication process
  - Disadvantages of this:
    - No room for error, if one bit is wrong the whole batch of ROMs must be thrown out
    - Data insertion step includes a relatively large fixed cost



# Programmable ROM (PROM)



- Less expensive alternative
- Nonvolatile and may be written into only once
- Writing process is performed electrically and may be performed by supplier or customer at a time later than the original chip fabrication
- Special equipment is required for the writing process
- Provides flexibility and convenience
- Attractive for high volume production runs

# Read-Mostly Memory



# Typical 16 Mb DRAM (4M x 4)

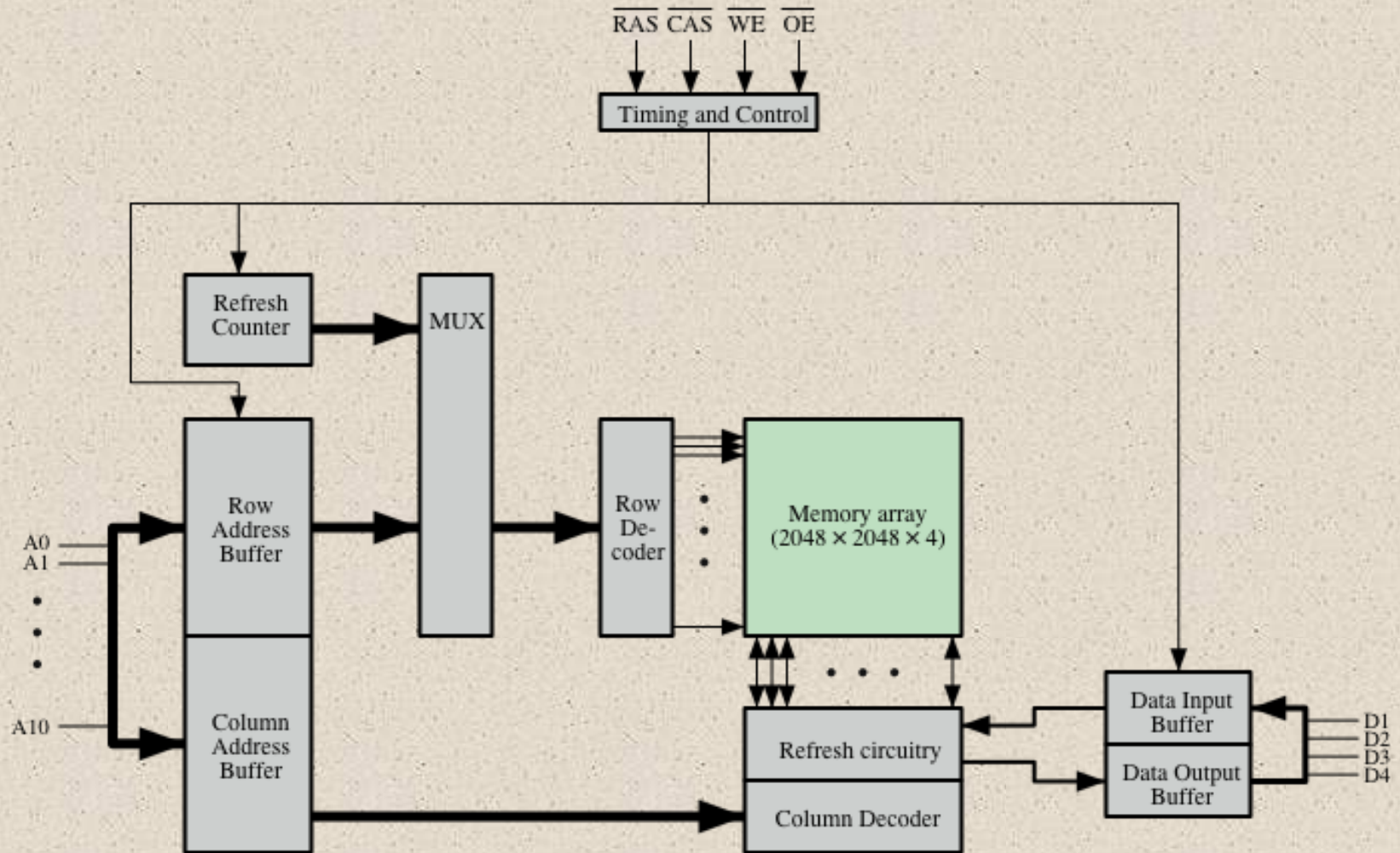


Figure 5.3 Typical 16 Megabit DRAM (4M x 4)

# Chip Packaging

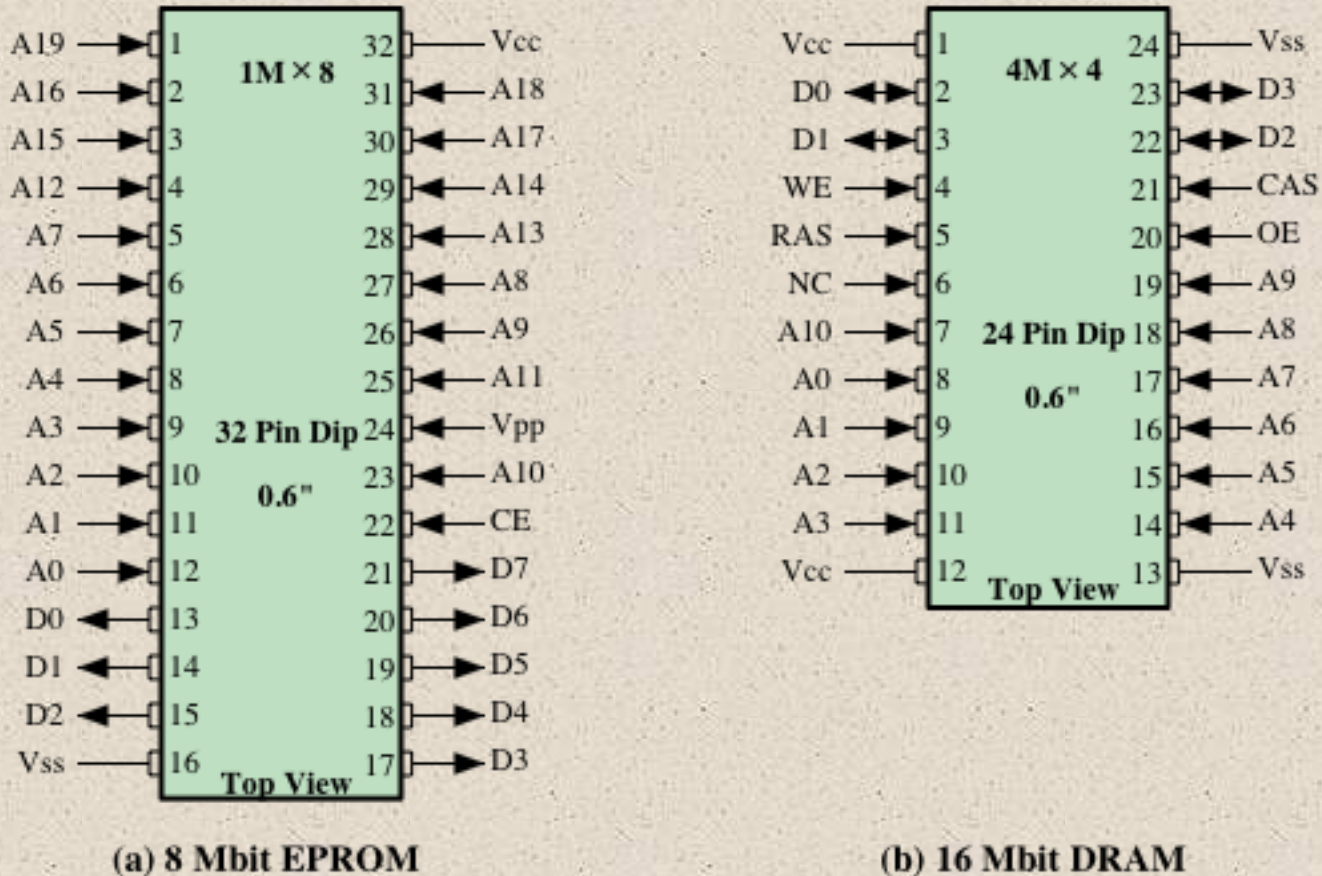


Figure 5.4 Typical Memory Package Pins and Signals

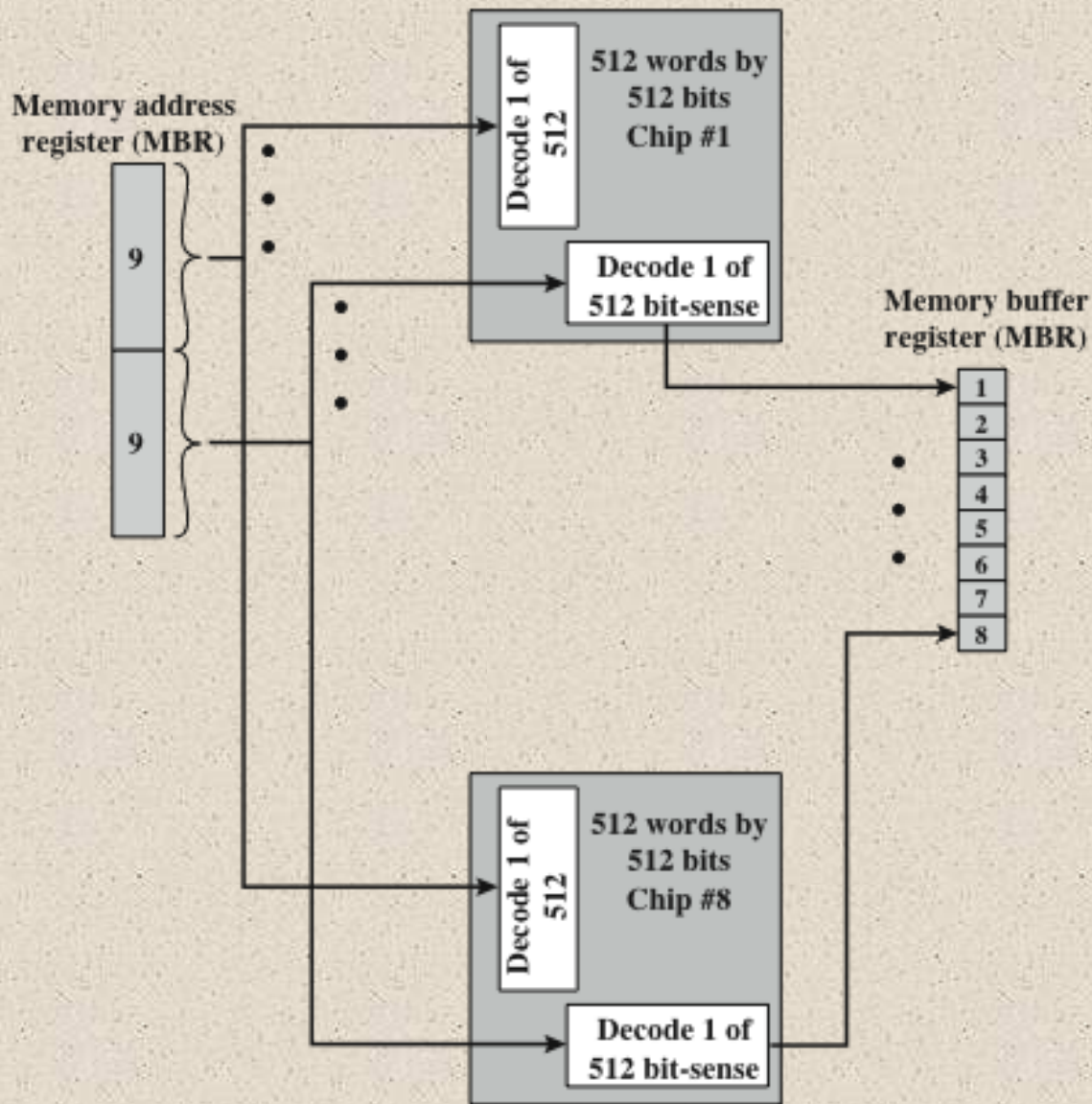
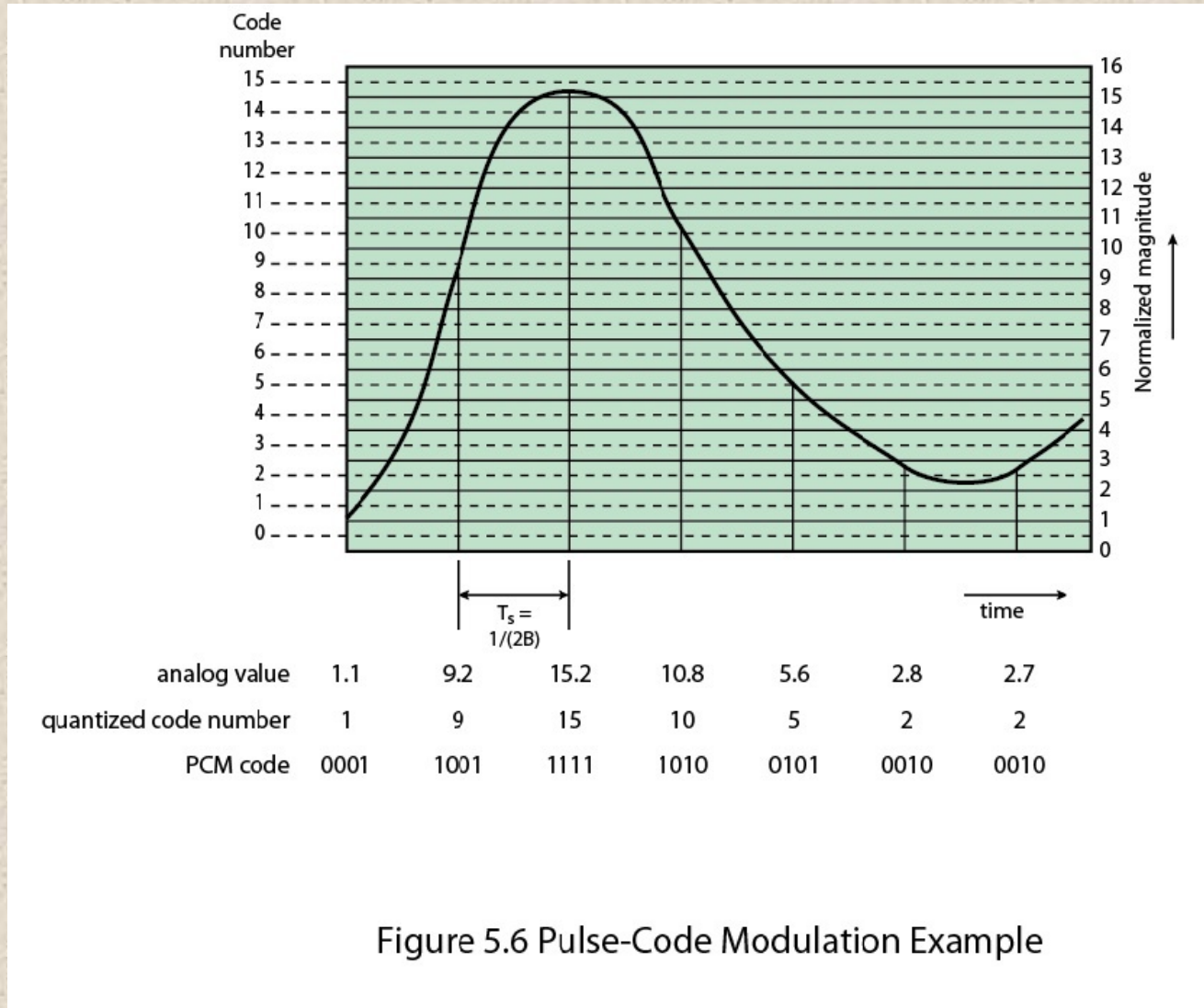


Figure 5.5

256-KByte  
Memory  
Organization

Figure 5.5 256-KByte Memory Organization

# 1 MByte Module Organization





# Interleaved Memory





# Error Correction



- Hard Failure
  - Permanent physical defect
  - Memory cell or cells affected cannot reliably store data but become stuck at 0 or 1 or switch erratically between 0 and 1
  - Can be caused by:
    - Harsh environmental abuse
    - Manufacturing defects
    - Wear
  
- Soft Error
  - Random, non-destructive event that alters the contents of one or more memory cells
  - No permanent damage to memory
  - Can be caused by:
    - Power supply problems
    - Alpha particles

# Error Correcting Code Function

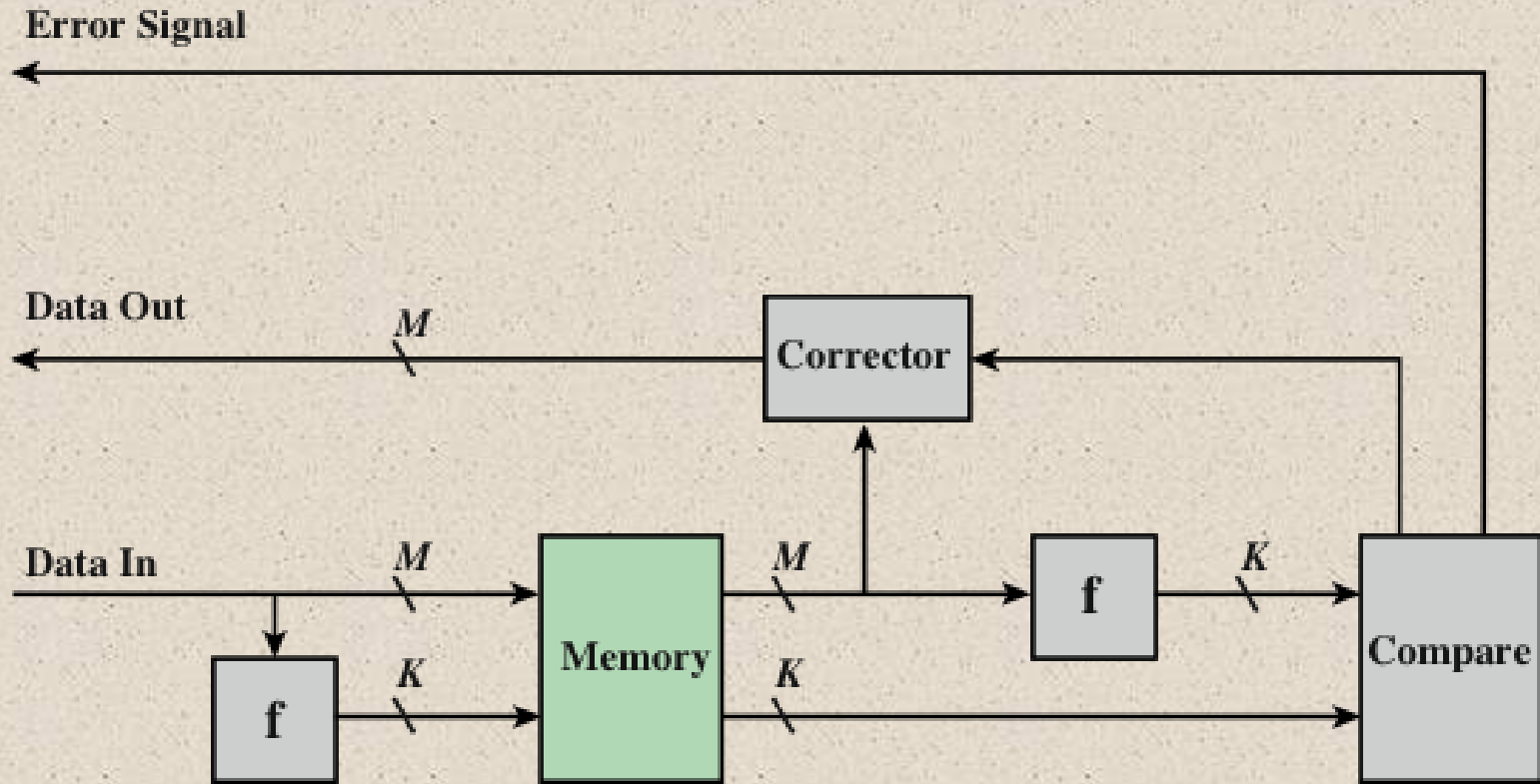


Figure 5.7 Error-Correcting Code Function



# Hamming Error Correcting Code

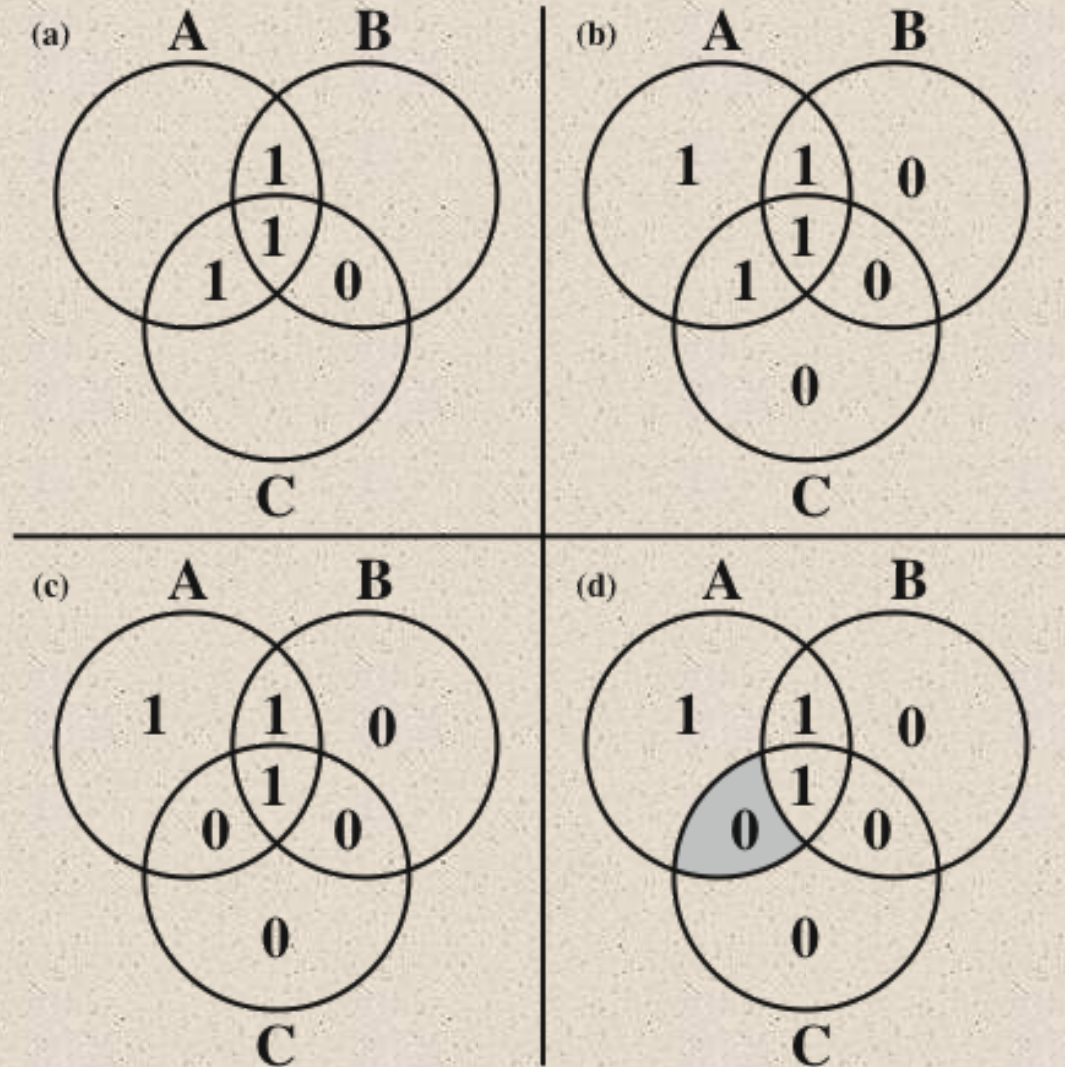


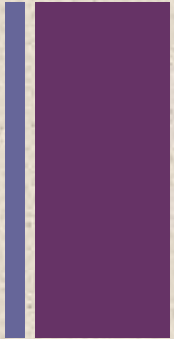
Figure 5.8 Hamming Error-Correcting Code

Table 5.3

# Performance Comparison DRAM Alternatives

	<b>Clock Frequency (MHz)</b>	<b>Transfer Rate (GB/s)</b>	<b>Access Time (ns)</b>	<b>Pin Count</b>
<b>SDRAM</b>	166	1.3	18	168
<b>DDR</b>	200	3.2	12.5	184
<b>RDRAM</b>	600	4.8	12	162

Table 5.3 Performance Comparison of Some DRAM Alternatives



# Layout of Data Bits and Check Bits

<b>Bit Position</b>	12	11	10	9	8	7	6	5	4	3	2	1
<b>Position Number</b>	1100	1011	1010	1001	1000	0111	0110	0101	0100	0011	0010	0001
<b>Data Bit</b>	D8	D7	D6	D5		D4	D3	D2		D1		
<b>Check Bit</b>					C8				C4		C2	C1

**Figure 5.9** Layout of Data Bits and Check Bits

# Check Bit Calculation

<b>Bit position</b>	12	11	10	9	8	7	6	5	4	3	2	1
<b>Position number</b>	1100	1011	1010	1001	1000	0111	0110	0101	0100	0011	0010	0001
<b>Data bit</b>	D8	D7	D6	D5		D4	D3	D2		D1		
<b>Check bit</b>					C8				C4		C2	C1
<b>Word stored as</b>	0	0	1	1	0	1	0	0	1	1	1	1
<b>Word fetched as</b>	0	0	1	1	0	1	1	0	1	1	1	1
<b>Position Number</b>	1100	1011	1010	1001	1000	0111	0110	0101	0100	0011	0010	0001
<b>Check Bit</b>					0				0		0	1

**Figure 5.10 Check Bit Calculation**



# Hamming SEC-DED Code

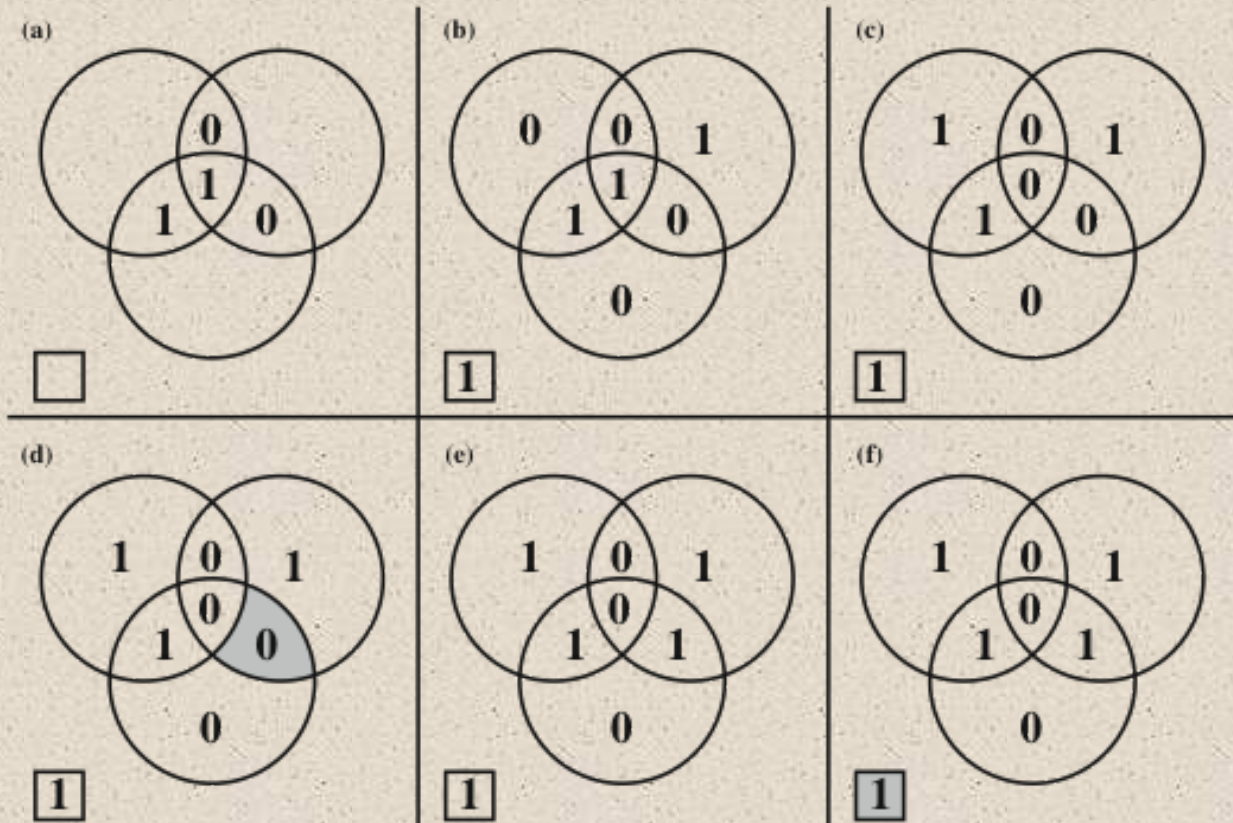


Figure 5.11 Hamming SEC-DED Code



# Advanced DRAM Organization

- One of the most critical system bottlenecks when using high-performance processors is the interface to main internal memory
- The traditional DRAM chip is constrained both by its internal architecture and by its interface to the processor's memory bus
- A number of enhancements to the basic DRAM architecture have been explored:

SDRAM

DDR-DRAM

RDRAM

+

	<b>Clock Frequency (MHz)</b>	<b>Transfer Rate (GB/s)</b>	<b>Access Time (ns)</b>	<b>Pin Count</b>
<b>SDRAM</b>	166	1.3	18	168
<b>DDR</b>	200	3.2	12.5	184
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Table 5.3 Performance Comparison of Some DRAM Alternatives

# Synchronous DRAM (SDRAM)



# SDRAM

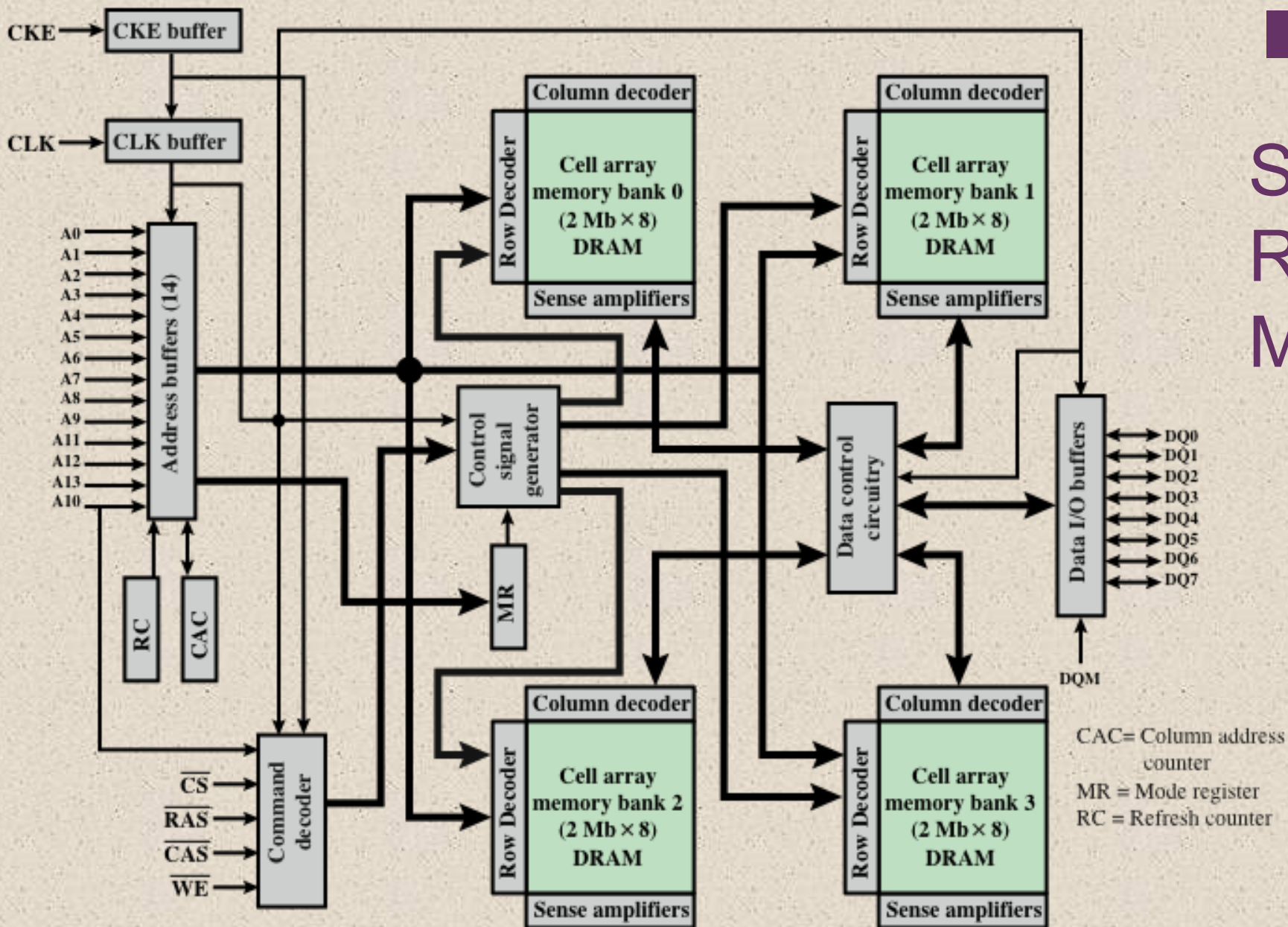
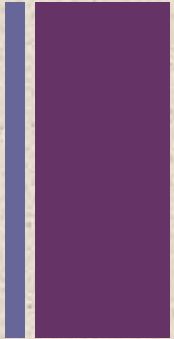


Figure 5.12 Synchronous Dynamic RAM (SDRAM)



# SDRAM Pin Assignments



A0 to A13	Address inputs
CLK	Clock input
CKE	Clock enable
$\overline{\text{CS}}$	Chip select
$\overline{\text{RAS}}$	Row address strobe
$\overline{\text{CAS}}$	Column address strobe
$\overline{\text{WE}}$	Write enable
DQ0 to DQ7	Data input/output
DQM	Data mask

Table 5.4 SDRAM Pin Assignments

# + SDRAM Read Timing

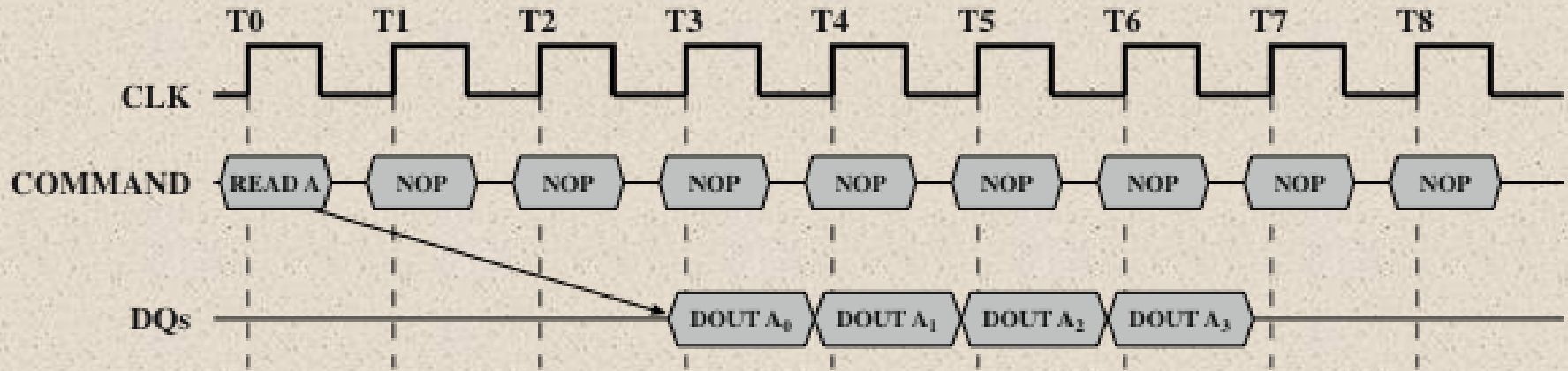
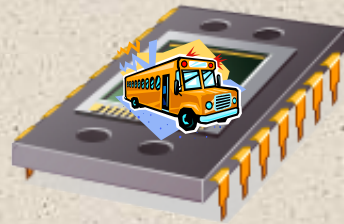


Figure 5.13 SDRAM Read Timing (Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2)

# RDRAM



+

# RDRAM Structure

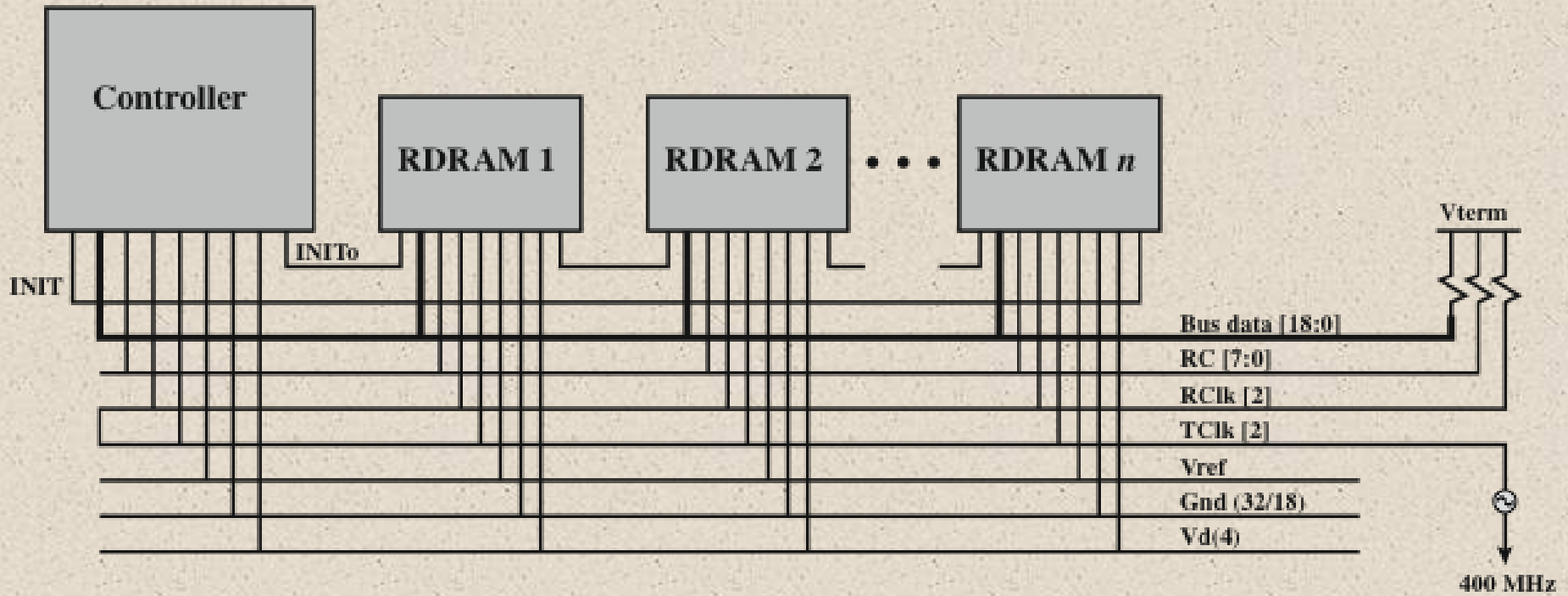
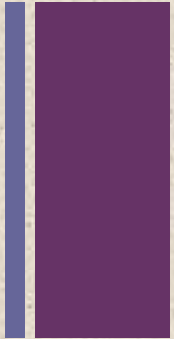


Figure 5.14 RDRAM Structure



# Double Data Rate SDRAM (DDR SDRAM)

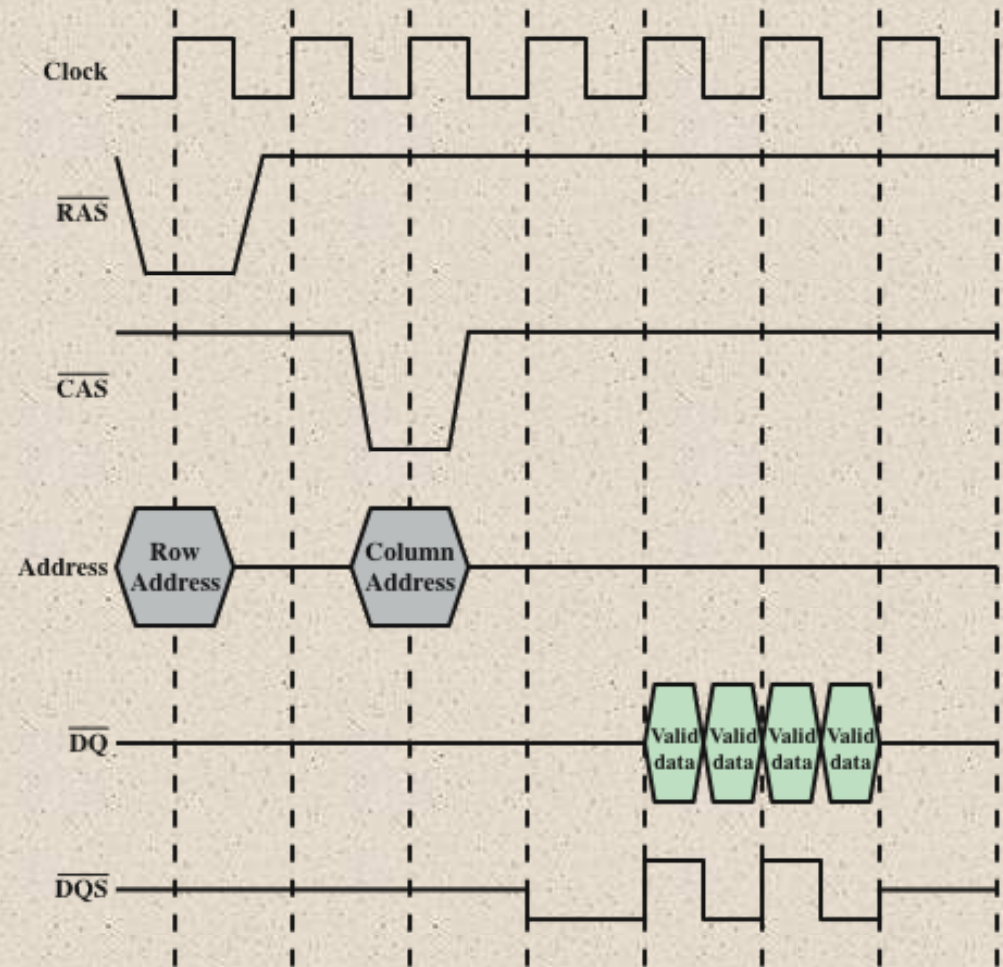


- SDRAM can only send data once per bus clock cycle
- Double-data-rate SDRAM can send data twice per clock cycle, once on the rising edge of the clock pulse and once on the falling edge
- Developed by the JEDEC Solid State Technology Association (Electronic Industries Alliance's semiconductor-engineering-standardization body)





# DDR SDRAM Read Timing



RAS = row address select  
CAS = column address select  
DQ = data (in or out)  
DQS = DQ select

Figure 5.15 DDR SDRAM Read Timing



# Cache DRAM (CDRAM)



- Developed by Mitsubishi
- Integrates a small SRAM cache onto a generic DRAM chip
- SRAM on the CDRAM can be used in two ways:
  - It can be used as a true cache consisting of a number of 64-bit lines
    - Cache mode of the CDRAM is effective for ordinary random access to memory
  - Can also be used as a buffer to support the serial access of a block of data

# + Summary

## Chapter 5

### Internal Memory

- Semiconductor main memory
  - Organization
  - DRAM and SRAM
  - Types of ROM
  - Chip logic
  - Chip packaging
  - Module organization
  - Interleaved memory
- Error correction
  - Hard failure
  - Soft error
- Hamming code
- Advanced DRAM organization
  - Synchronous DRAM
  - Rambus DRAM
  - DDR SDRAM
  - Cache DRAM